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Physical, electrical and logical test specification;
Part 1: Terminal features
(Release 13)

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Part 1: "Terminal features";

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Introduction

The present document defines the interface tests for the Terminal/UICC interface.

The aim of the present document is to ensure interoperability between an UICC and a Terminal independently of the respective manufacturer, card issuer or operator.

Application specific tests for applications residing on an UICC are specified in ETSI TS 131 121 [4].

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